

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/714,012	<b>Applicant(s)/Patent under Reexamination</b> HSIEH, WU-HONG
	<b>Examiner</b> Kim R. Lockett	<b>Art Unit</b> 2837

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
Same as above	8/29/05	an	